

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>		Docket Number (Optional) MCS-101-99		Application Number 09/536,820	
		Applicant(s) Huang et al.			
		Filing Date 3/27/2000		Group Art Unit Unknown	
*EXAMINER INITIAL	OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>				
UK	C	T. Cootes, G. Edwards, and C. Taylor, "Active Appearance Models," ECCV.			
UK	D	D. Beymer, "Face Recognition Under Varying Pose," AI Memo 1461.			
UK	E	D. Beymer and T. Poggio, "Face Recognition From One Model View," Proc. Fifth Int'l Conf. Computer Vision, 1995.			
UK	F	T. Vetter and T. Poggio, "Linear Object Classes and Image Synthesis From a Single Example Image," IEEE Trans PAMI.			
UK	G	A. Pentland, B. Moghaddam, and T. Starner, "View-Based and Modular Eigenspaces for Face Recognition," IEEE CVPR.			
UK	H	S. Nayar, H. Murase, and S. Nene, "Parametric Appearance Representation," Early Visual Learning.			
UK	I	Hansen L K, Liisberg C, Salamon P. Ensemble Methods for Handwritten Digit Recognition. In: Proceedings of the 1992 IEEE SP Workshop, 1992, Vol.2, 333~342.			
UK	J	Filippi E, Costa M, Pasero E. Multi-layer Perceptron Ensembles for Increased Performance and Fault-Tolerance in Pattern Recognition Tasks. In: Proceedings of the 1994 IEEE International Conference on Neural Networks, 1994, Vol.5, 2901~2906.			
UK	K	Kirkland J. Squad-based Expert Modules for Closing Diphthong Recognition. In: Proceedings of the Second New Zealand International Two-Stream Conference on Neural Networks and Expert Systems, 1995, 302~305.			
UK	L	Shimshoni Y, Intrator N. Classification of Seismic Signals by Integrating Ensembles of Neural Networks. IEEE Transactions on Signal Processing, 1998, 46(5): 1194~1201.			
UK	M	Gutta S, Wechsler H. Face Recognition Using Hybrid Classifier Systems. In: Proceedings of the 1996 IEEE International Conference on Neural Networks, 1996, Vol.2, 1017~1022.			
UK	N	Gutta S, Huang J, Takacs B, Wechsler H. Face Recognition Using Ensembles of Networks. In: Proceedings of the 13th International Conference on Pattern Recognition, 1996, Vol.4, 50~54.			
EXAMINER <i>Vijaya KPR</i>		DATE CONSIDERED 2/13/03			
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					

